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1	INZZ	(automatic OR intelligent OR computerized) ADJ (door OR entry)	unrestricted	41	show titles
2	INZZ	self ADJ diagnosis	unrestricted	471	show titles
3	INZZ	1 AND 2	unrestricted	0	-
4	INZZ	(central OR remote) ADJ (management OR managerial OR administrative)	unrestricted	367	show titles
5	INZZ	1 AND 3	unrestricted	0	-

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- Classification codes A: Physics, 9
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- Basic
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- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
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(automatic <phrase> door)

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1 Automatic door opener

Pik-Yiu Chan; Enderle, J.D.;
Bioengineering Conference, 2000. Proceedings of the IEEE 26th Annual Northeast , 8-9 April 2000
Pages:139 - 140

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE CNF**

2 A habituation, rehabilitation, and recovery chip

Goru, V.K.; Akers, L.A.;
Circuits and Systems, 1996. ISCAS '96., 'Connecting the World'., 1996 IEEE International Symposium on , Volume: 3 , 12-15 May 1996
Pages:487 - 490 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(324 KB\)\]](#) **IEEE CNF**

3 Wheelchair assist devices

Chanchavac, S.; Jain, A.; Pham, D.; Pruehsner, W.; Enderle, J.D.;
Bioengineering Conference, 2001. Proceedings of the IEEE 27th Annual Northeast , 31 March-1 April 2001
Pages:97 - 98

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Tables of Contents

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- Conference Proceedings
- Standards

Search

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- Basic
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

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- Access the IEEE Member Digital Library

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- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

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Select years to search:

From year: to

Organize search results by:

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 List

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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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- Access the IEEE Enterprise File Cabinet

 [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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Welcome to IEEE Xplore®

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- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
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- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
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Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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 [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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